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LIST OF REFERENCES CITED BY

APPLICANT

(REVISED FORM PTO-1449)

DATED: July 26, 2004

Atty. Docket No.	Serial No.:
4629	10/753,095

Applicant: Kenzou KASSAI et al.

U.S. Piling Date: January 6, 2004 Art Unit: 3611

U. S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NO.								DATE	NAME	cl.	Sub- Cl.	Fil. Date
\mathcal{B}	AD	3	9	8	9	2	9	5	11/1976	Sparkes	-	-	_
"BA-	AE	4	2	5	6	3	2	5	03/1981	Pleischer	-		-
BA	AF	4	5	1	5	3	8	9	05/1985	Kassai	-	_	-

FOREIGN PATENT DOCUMENTS

		DOC	TME	י יייני	NO.			22.00		_,	Sub-	Trans.	
DOCUMENT NO.							 	DATE	COUNTRY	C1.	Cl.	Yes	No

OTHER DOCUMENTS

EXAMINER Budert Aren

DATE CONSIDERED

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LIST OF REFERENCES CITED BY APPLICANT (REVISED FORM PTO-1449)										Applicant: Kenzou KASSAI et al.					
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U. S. PATENT DOCUMENTS															
*EXAMINER INITIAL		DOCUME	TV.	МО	٠.				DATE	NAME		c1.	Sub- Cl.	Fil. Date	
BA	AA	5	6	7	6	4	1	9	10/1997	Kassai		-	-	_	
FOREIGN PATENT DOCUMENTS															
		DOCUMEN	4T	Ю	٠.				DATE	COUNTRY	c1.	Sub- Cl.	Yes	No	
7BA	AB	0	6	9	7	3	2	3	02/1996	EP	-	-	=AA		
BA	AC	08	0	5	8	5	9	9	03/1996	Japan	-	Abstr., ≤AA, AB			
OTHER DOCUMENTS															
EXAMINER B-Sthery DATE CONSIDERED 01/05/06															
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